Special Issue

Security, Privacy and Application in New Intelligence Techniques

Message from the Guest Editors

This Special Issue is dedicated to the most recent developments and research outcomes addressing the related theoretical and practical aspects on security, privacy and application in new intelligence techniques, and the goal is to provide worldwide researchers and practitioners an ideal platform to innovate new solutions targeting at the corresponding key challenges. Original and unpublished high-quality research results are solicited to explore various challenging topics.

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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